Trapped atoms as a source of cold electrons

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Coherence and Quantum Technology group

with Wouter Engelen, Daniël Bakker, Bas van der Geer, Rick van Bijnen, Nicola Debernardi, Jom Luiten and many others

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Where innovation starts

Big thanks to ...

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- for organizing this
- coming up with the idea
- venue, finances
- scientific program
- in France (Nimes)









Ultrafast microscopy and diffraction

Structural dynamics... resolve atomic length and time scales:

1 Å @ 100 fs (as)





CeO₂ catalyst nanoparticle

Myoglobin



Microscopy developments



Using pulsed lasers & photo-cathodes

Dynamic Transmission Electron Microscope (DTEM): nanosecond single-shot images

Reed, Browning et al, Livermore Nat'l Lab

LaGrange et al, APL 89 (2006) 044105

"Four-dimensional ultrafast electron microscopy": sub-ps multi-shot images & diffraction patterns

Zewail group, CalTech

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Lobastov et al, PNAS 102 (2005) 7069



100fs @ 80MHz single electrons



Ultrafast electron/X-ray diffraction



Electrons: Miller group (Toronto, MPSD/CFEL), Zewail group (CalTech), Carbone group (EPFL), Siwick group (McGill), Baum group (LMU/MPQ), ... X-rays: XFEL (LCLS), European XFEL & FLASH @ DESY, SwissFEL@PSI, FERMI@ELETTRA, ...



Diffraction example

Siwick, Dwyer, Jordan and Miller,

An Atomic-Level View of Melting Using Femtosecond Electron Diffraction

(a)







An atomic-level view of melting (a) Diffraction patterns showing the progress of a laserinduced polycrystalline to liquid phasetransition in Al. The structural rearrangements take only 3.5 ps (1ps = 10^{-12} s) (b) The face centered cubic (FCC) structure of Al. Atoms have been colour-coded such that each colour represents a given distance from the central black atom. (c) The time-dependent spectrum of interatomic spacings, G(r,t), at different stages through the phase transition. The correspondence between the peaks in G(r) and the FCC Al lattice are shown for the first four peaks by labeling with the same colour as in (b). Longrange ordering in atomic position is almost entirely preserved for the first 1.5 ps, but decays after this time such that a liquid-like atomic configuration is reached by 3.5 ps.



Science 302 (2003) 1382

Eindhoven ultrafast electron source

Jom Luiten and coworkers

We are taking orders Only € 99,999.99



Single-shot UED setup

Thijs van Oudheusden, Peter Pasmans, Stefano dal Conte and Jom Luiten

Van Oudheusden et al., JAP **102** (2007) 093501 Van Oudheusden et al., PRL 105 (2010) 264801 50 fs sub-ps 100 kV 3 GHz RF cavity longitudinal E-field



SINGLE SHOT 0.1 pC (10⁶ e) , 100 keV polycrystalline Au foil

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Single-shot UED summary



- Cu photo-cathode
- Q = 0.1 pC *single-shot*
- bunch length < 1ps ultrafast
- transverse coherence length 3 nm (0.2 mm spot size = typical)

limited to "small" periodicity (*ex:* gold crystals) what about larger structures?

s)

biomolecules

Increase transverse coherence length



field or photo-emission source: $kT_e = 0.5 \text{ eV} \rightarrow T = 5000 \text{ K}$

UltraCold Electron Source $\left\{\begin{array}{c}10K \rightarrow 20x \text{ larger } L_c\\\text{"single-shot" (1M e)}\end{array}\right.$

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Magneto-Optical atom Trap (MOT)



Laser cooling & trapping: (Nobel 1997) 6 laser resonant beams + quadrupole magnetic field

N = few 10⁸ rubidium atoms σ = 0.9 mm, n = 10¹⁰ cm⁻³ T < 0.001 K

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Ultracold Plasma by photo-ionization



Rolston, Killian, Bergeson, Pillet, Comparat ...

2012 ColdBeams Meeting Nimes

Electron temperature



 $\tau = 1 \ ps \to T_e = 10 \ K$ & plasma effects



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Ultracold electron source

Ultrafast electron diffraction (TU/e, Scholten) Low-energy microscopy (Orsay)



Photo-electron sources

Not an entirely new idea: low energy-spread electron beams for electron-atom/molecule collisions

1974: *Gallagher and York*, RSI 45, 662 < 1 fA, meV resolution, Ba beam + intra-cavity HeCd-laser

1994: *Klar, Hotop et al*, Meas. Sci. Technol. 5, 1248 1 fA current, < 1 meV energy spread, Ar* beam + CW tuneable dye laser

2010 Kurokawa et al, PRA 82, 062707 (2010) Ar gas + synchrotron radiation

What's new?

- Applications (structural dynamics)
- Ultrafast operation (pulse length, peak current, charge density)
- Cold atom techniques → increased control charge shaping: McCullogh, Scholten et al, Nat Phys 7 (2011) 785

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Ultracold electron AND ion source

Focused ion beams & ion microscopy, ion-on-demand, implantation (McClelland, TU/e, Comparat, Weatherill) **UCES: Rb**⁺ T_e≈ **15 K** UCIS **MOTIS** Luiten group @ TU/e: T_. ≈ **1 mK** develop into practical source **1 eV ion beams** - investigate properties: cold! 20 meV energy spread Technische Universiteit **Eindhoven** University of Technology



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02-10-12

Atom trap inside coaxial accelerator (cross section)



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Electron temperature from spot size



linear beam transport $\sigma_{x_f}^2 = A^2 \sigma_{x_i}^2 + B^2 \sigma_{\alpha_i}^2$

 $\begin{bmatrix} x_f & x_i & \alpha_i \\ spot & source & diver-\\size & size & gence\\ measure & known & extract \end{bmatrix}^{\alpha_i}$

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transport coefs A,B known



28-01-2010

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Electron spot size vs. beam energy: "waist scan"

data & GPT particle tracking simulations



Temperature vs. excess energy



Temporal bunch length



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- τ = 2 ns *rms* @ 30 cm
- limited by pulse length laser (YAG-pumped dye)
- photo-ionization in a DC field
- would like shorter bunches < 1 ps

Shorter bunches: "frozen" Rydberg gas

- pulsed field-ionization of excited Rydberg atoms
- principal quantum number n
- higher $n \rightarrow$ lower ionization field \rightarrow smaller U



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Field ionization experiment: "waist scan"



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Faster pulses: femtosecond OPA







data s' data s2 model s1

model s2

2.5



- vary wavelength and field strength (excess energy)
- similar analysis → source temperature

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Femtosecond OPA results



2011: still achieve T ≈ 25 K near threshold ! (?)

Scholten (Melbourne): similar results

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Dynamics: potential landscape



Classical electron trajectories



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Electron trajectories: forward emission



Femtosecond OPA results vs. Bordas model



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- dynamics model (Bordas) explains fs data ! (?)
- possible to get few K electrons with fs lasers

Temporal structure: ps time resolution

Also: Scholten et al, Melbourne

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Streak-Camera Probing of Rubidium Rydberg Wave Packet Decay in an Electric Field

G. M. Lankhuijzen and L. D. Noordam



FIG. 2. Measured decay of an autoionizing electronic wave packet (full line). The wave packet is created above the classical field ionization limit at a scaled energy of $\epsilon = -1.54$. The laser polarization is perpendicular to the electric field of 2.0 kV/cm. The calculated angular recurrence time using the hydrogenic model is $\tau_k = 5.7$ ps. The dotted line is an exponential fit with a decay time of 16 ps.

different context: series of papers by Noordam, Robicheaux, Van Linden van den Heuvell, Vrakking (1993-2000)

Few-ps time resolution is possible !

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Application: diffraction patterns from graphite flakes



use this to measure coherence length

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?

Conclusions

- Demonstrated application of the UCP: ultracold electron (and ion) source
- Alternate way to achieving high brightness; large coherence length; low energy spread
- Applications in UED, FIB and electron/ion microscopy
- Ultrafast & cold electron source for UED

 $T \approx 25 K$, $\tau < 1 ns$ (ps), $10^5 e p.p.$

quantum degenerate electron beams? n=10¹⁸/m³, T=1 mK

Claessens *et al.*, PRL **95**, 164801 (2005) Claessens *et al.*, Phys. Plasmas **14**, 093101 (2007) Van der Geer *et al.*, JAP **102**, 094312 (2007) Taban *et al.*, PRST-AB **11**, 050102 (2008) Reijnders *et al.*, PRL **102**, 034802 (2009) V.d. Geer *et al.*, Microscopy and Microanalysis **15**, 282 (2009) Reijnders *et al.*, PRL **105**, 034802 (2010) Taban *et al.*, EPL **91**, 46004 (2010) Reijnders *et al.*, JAP **109**, 104308 (2011) Vredenbregt and Luiten, Nat. Phys. **7**, 747 (2011)



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